



**HEWLETT
PACKARD**

10-1500 MHz T0-8 CASCADABLE AMPLIFIER

**HAMP-1003
HAMP-1003TXV**

TECHNICAL DATA APRIL 1985

Features

WIDE 1 dB BANDWIDTH
5-2100 MHz

EXCEPTIONAL PHASE LINEARITY
1.6 Degree Deviation from 100 to 1500 MHz

LOW VARIATION OVER TEMPERATURE

OUTPUT POWER
6.5 dBm

EASILY CASCADABLE IN A 50 OHM SYSTEM

Description/Applications

The HAMP-1003 is a thin-film hybrid amplifier using bipolar transistors. The design uses resistive feedback which provides exceptional phase linearity and high performance over a wide temperature range and bandwidth. The internal bias network and coupling capacitors eliminate the need for external support circuitry.

This amplifier is ideal for IF, RF and high speed digital applications.

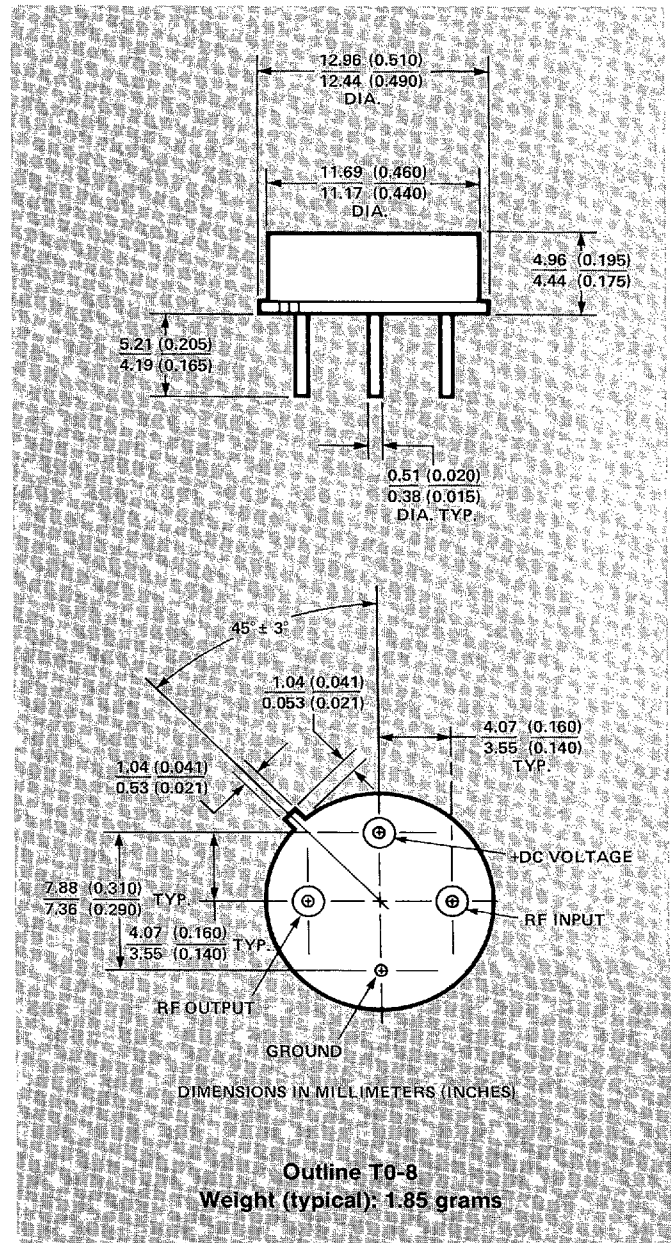
The HAMP-1003 is supplied in a standard rugged four leaded T0-8 hermetic package.

Absolute Maximum Ratings*

DC Voltage	30.0 V
Continuous RF Input Power	+15 dBm
Short Term RF Input Power	+20 dBm
(CW/1 Minute Duration)	
Max. Input Peak Power	+27 dBm
(3 Microsecond Pulse, One Single Pulse)	
Operating Case Temperature	-55° C to 125° C
Storage Temperature	-65° C to 150° C

*Operation in excess of any one of these conditions may result in permanent damage to this device.

MTTF: (Calculated, MIL-STD-217D): 1.2×10^7 Hours at Case Temperature +85° C.



Electrical Specifications (Measured in 50 Ohm System at +15 V)

Characteristic	Typical at 25°C	Guaranteed	
		0-50°C	-55 – +85°C
Frequency Range (MHz)	10-1500	10-1500	10-1500
1 dB Bandwidth (MHz)	5-2100		
Gain Max. (dB)	10.1	10.5	10.6
Gain Min. (dB)	9.7	9.1	9.0
Gain Flatness Max. (dB)	±0.15	±0.5	±0.5
Maximum Deviation from Linear Phase 100-1500 MHz (°)	1.6		
Noise Figure Max. (dB)	5.0	5.5	6.0

Characteristic	Typical at 25°C	Guaranteed	
		0-50°C	-55 – +85°C
Power Output at 1 dB Compression (Min.) (dBm)	6.5	3.8	3.0
VSWR Input/Output Max.	1.7	2.0	2.0
Second Order Harmonic Intercept Point (dBm)	25.0		
Second Order Two Tone Intercept Point (dBm)	22.0		
Third Order Two Tone Intercept Point (dBm)	15.0		
DC Current (mA)	39.0		

Typical Performance

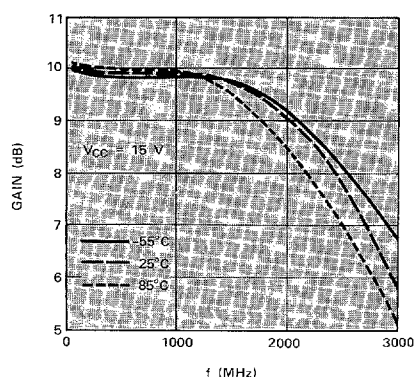


Figure 1. Gain at Three Temperatures

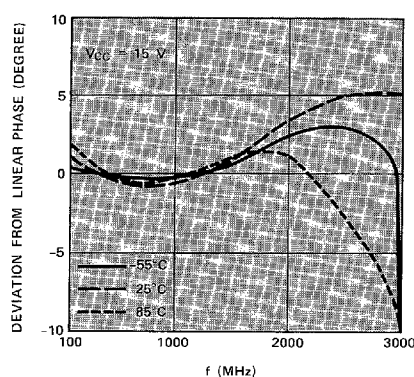


Figure 2. Phase at Three Temperatures

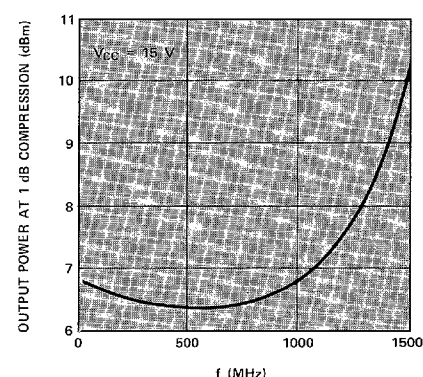


Figure 3. P_{1dB} at 25°C

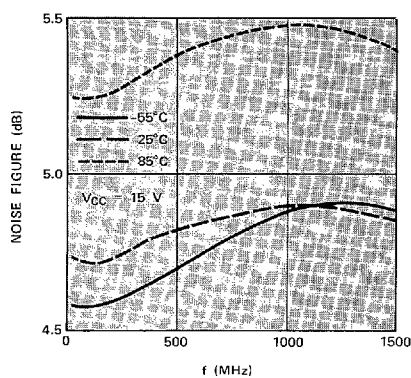


Figure 4. Noise Figure at Three Temperatures

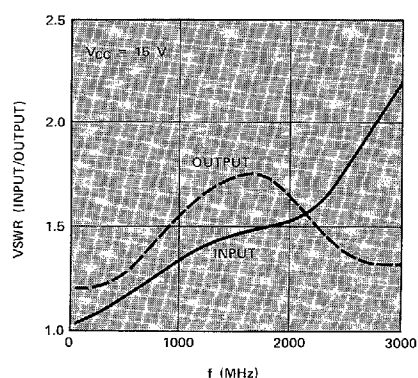


Figure 5. Input/Output VSWR at 25°C

Typical S-Parameters at 25°C

Frequency (MHz)	S ₁₁		S ₂₁		S ₁₂		S ₂₂	
	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.	Mag.	Ang.
100	0.017	-84	3.15	172	0.113	2	0.078	-18
200	0.029	-102	3.14	168	0.112	1	0.074	-30
300	0.040	-94	3.13	162	0.112	2	0.096	-47
400	0.054	-96	3.11	155	0.114	3	0.105	-52
500	0.069	-97	3.13	148	0.114	4	0.117	-62
600	0.082	-100	3.10	143	0.116	5	0.140	-69
700	0.099	-105	3.11	136	0.116	5	0.155	-73
800	0.114	-109	3.12	129	0.117	6	0.168	-79
900	0.130	-113	3.10	123	0.119	7	0.192	-84
1000	0.143	-118	3.15	117	0.121	8	0.207	-88
1100	0.158	-124	3.13	111	0.123	9	0.222	-93
1200	0.166	-130	3.12	103	0.128	8	0.236	-99
1300	0.178	-138	3.13	97	0.127	9	0.246	-105
1400	0.186	-145	3.07	91	0.130	9	0.261	-110
1500	0.190	-155	3.06	84	0.134	9	0.264	-116
1600	0.197	-164	3.02	77	0.140	10	0.266	-122
1700	0.200	-175	3.01	71	0.143	10	0.273	-129
1800	0.197	173	2.96	64	0.149	8	0.267	-135
1900	0.198	160	2.91	58	0.151	7	0.258	-143
2000	0.202	145	2.90	51	0.158	7	0.252	-151
2100	0.212	131	2.79	43	0.165	4	0.237	-160
2200	0.221	115	2.74	37	0.165	3	0.220	-169
2300	0.233	99	2.69	30	0.171	3	0.197	-179
2400	0.249	83	2.56	23	0.178	0	0.173	167
2500	0.272	68	2.49	16	0.179	-2	0.156	153
2600	0.294	55	2.37	9	0.180	-4	0.136	135
2700	0.322	42	2.30	3	0.187	-5	0.127	115
2800	0.347	31	2.17	-3	0.192	-8	0.125	94
2900	0.368	20	2.07	-10	0.193	-11	0.132	73
3000	0.377	10	1.97	-16	0.191	-13	0.151	59

Typical Performance Parameters at 25°C

Frequency (MHz)	Linear Phase Deviation (deg.)	Relative Phase (deg.)	Gain Deviation (dB)	Gain Absolute (dB)	Group Delay (ns)	Input VSWR	Output VSWR
10				10.00		1.30	1.40
100	1.56	0	0.10	9.98	0.22	1.03	1.17
200	0.07	-5	0.07	9.95	0.13	1.06	1.16
300	-0.51	-11	0.04	9.92	0.16	1.08	1.21
400	0.01	-18	-0.01	9.87	0.19	1.11	1.24
500	0.01	-24	0.04	9.92	0.18	1.15	1.26
600	-0.63	-30	0.04	9.83	0.16	1.18	1.32
700	-0.20	-36	-0.01	9.86	0.19	1.22	1.37
800	0.16	-43	0.01	9.88	0.18	1.26	1.41
900	-0.34	-49	-0.05	9.83	0.17	1.30	1.48
1000	-0.93	-55	0.08	9.96	0.16	1.33	1.52
1100	-0.63	-62	0.03	9.91	0.19	1.37	1.57
1200	0.39	-69	-0.00	9.88	0.21	1.40	1.62
1300	0.53	-75	0.03	9.90	0.18	1.43	1.65
1400	0.48	-82	0.13	9.74	0.18	1.46	1.71
1500	0.51	-88	-0.16	9.72	0.18	1.47	1.72
1600	1.54	-96	-0.27	9.65	0.21	1.49	1.73
1700	0.85	-101	-0.30	9.58	0.16	1.50	1.75
1800	1.37	-103	0.46	9.45	0.19	1.45	1.73
1900	3.26	-116	0.60	9.22	0.23	1.49	1.69
2000	2.35	-122	0.63	9.25	0.15	1.51	1.67
2100	3.66	-129	-0.96	8.92	0.21	1.54	1.62
2200	3.58	-136	-1.12	8.75	0.17	1.57	1.56
2300	3.86	-143	-1.29	8.59	0.18	1.61	1.49
2400	4.37	-149	-1.71	6.17	0.19	1.66	1.42
2500	4.88	-156	-1.94	7.94	0.19	1.75	1.37
2600	5.60	-163	-2.39	7.49	0.20	1.83	1.31
2700	5.11	-169	-2.64	7.24	0.16	1.95	1.29
2800	5.34	-176	-3.15	6.73	0.18	2.06	1.28
2900	5.13	-183	-3.55	6.30	0.17	2.17	1.30
3000	5.20	-183	-4.00	5.83	0.18	2.21	1.36

Since the advantages of products tested to well established reliability screening standards can be of significant value to reliability oriented customers, HP makes available products with Hi-Rel screening and testing patterned after MIL-STD-883, Method 5004.2 latest revision.

The table below depicts the screening program for this family of amplifiers.

100% SCREENING PROGRAM

Screening Test/Inspection	MIL-STD-883 Test Method	Conditions/Comments
1. Internal Visual Inspection (PreCap)	2017	
2. High Temperature Storage (Stabilization Bake)	1008	Condition B T = 125°C, t = 24 hours
3. Temperature Cycling	1010	Condition B -55° to 125°C
4. Constant Acceleration	2001	Condition B 20 kg's, Y ₁ Direction
5. Pre Burn-in Electrical	—	Per Applicable Device Specification
6. Burn-in	1015	t = 168 hours T _C = 80% of Rated Case Temp. and 80% of Rated Bias Conditions
7. Post Burn-in Electrical (PDA ≤10%)	—	Per Applicable Device Specification
8. Hermeticity Tests (Fine and Gross)	1014	Conditions A and C
9. Final Electrical Tests	—	Per Applicable Device Specification
10. External Visual Inspection	2009	

Note: Additional tests, screens and qualification testings (e.g.: X-ray, PIND, Extended Burn-in, Group A, B, C and D) are available on request.

Ordering Information

Add suffix TXV to standard part number.

Example: Standard Product HAMP-1003
 Hi-Rel Product HAMP-1003TXV

4447584 0016792 575

For more information call your local HP sales office listed in the telephone directory white pages. Ask for the Components Department. Or write to Hewlett-Packard: **U.S.A.** — P.O. Box 10301, Palo Alto, CA 94303-0890. **Europe** — P.O. Box 999 1180 AZ Amstelveen, The Netherlands. **Canada** — 6877 Goreway Drive, Mississauga, L4V 1M8, Ontario. **Japan** — Yokogawa-Hewlett-Packard Ltd., 3-29-21, Takaido-Higashi, Suginami-ku, Tokyo 168. **Elsewhere** in the world, write to Hewlett-Packard Intercontinental, 3495 Deer Creek Road, Palo Alto, CA 94304.

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Data Subject to Change

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